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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Shunpei Yamazaki et al. Art Unit : 2815
Serial No. : 10/693,491 Examiner : Paul E. Brock II
Filed : October 27, 2003
Title : SEMICONDUCTOR DEVICE AND FABRICATION METHOD THEREOF

MAIL STOP AMENDMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450


INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form. Copies of any listed U.S. patents or U.S. patent application publications can be provided upon request.

This statement is being filed after a first Office action on the merits, but before receipt of a final Office action or a Notice of Allowance. A check for \$180 in payment of the late submission fee of \$1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 4/15/05



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Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No.
12732-097002Application No.
10/693,491**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

(37 CFR §1.98(b))

Applicant
Shunpei Yamazaki et al.Filing Date
October 27, 2003Group Art Unit
2815**U.S. Patent Documents**

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	2001-0025960	10/04/2001	Ohtani et al.			05/17/2001
	AB	2004-0051142	03/18/2004	Yamazaki et al.			08/14/2003
	AC	2005-0017242	01/27/2005	Yamazaki et al.			08/17/2004
	AD	2005-0051773	03/10/2005	Nakajima			09/21/2004
	AE	6,259,138	07/10/2001	Ohtani et al.			12/16/1999
	AF	6,545,359	04/08/2003	Ohtani et al.			12/16/1999
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	AH	6,809,021	10/26/2004	Ohtani et al.			02/03/2003
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AQ	
	AR	
	AS	
	AT	

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.